





an Open Access Journal by MDPI

Microwave Imaging and Its Application

Guest Editor:

Prof. Dr. Raffaele Solimene

Dipartimento di Ingegneria, Università degli Studi della Campania, 81031 Aversa, Italy

Deadline for manuscript submissions:

closed (30 September 2019)

Message from the Guest Editor

The aim of this Special Issue is to collect contributions from scientists working in this field and in all the pertinent applicative contexts that provide recent advances in microwave imaging, including hardware design, image reconstruction methods, computational methods and experimental verification under realistic conditions.

Topics of interest for this Special Issue include, but are not limited to:

- Novel electromagnetic scattering models
- Linear and non-linear inversion methods and achievable performance
- Passive and/or non-cooperative source microwave imaging
- Information theoretic approaches for data selection and performance computation
- Numerically efficient inversion algorithms
- Hardware and antenna design
- Experimental in situ verification
- Antenna deconvolution and clutter rejection for near- and very nearzone configuration
- Phase only data microwave imaging

Please find more information here!

Welcome to conribute!











an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science),

CAPlus / SciFinder, Inspec, and other databases.

Journal Rank: JCR - Q2(*Electrical and Electronic Engineering*) CiteScore - Q2 (*Electrical and Electronic Engineering*)

Contact Us